- Supply Current of 40 μA (Max)
- Battery Supply Current of 100 nA (Max)
- Supply Voltage Supervision Range:
 Adjustable
 - Other Versions Available on Request
- Backup-Battery Voltage Can Exceed V_{DD}
- Power-On Reset Generator With Fixed 100-ms Reset Delay Time
- Active-High and Active-Low Reset Output
- Chip-Enable Gating . . . 3 ns (at V_{DD} = 5 V) Max Propagation Delay
- 10-Pin MSOP Package
- Temperature Range . . . –40°C to 85°C

description

The TPS3613-01 supervisory circuit monitors and controls processor activity by providing backup-battery switchover for data retention of CMOS RAM.

typical applications

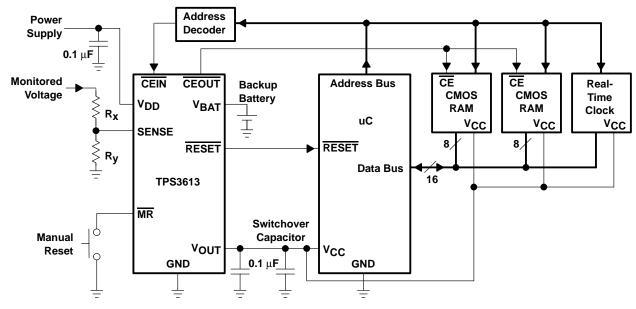
- Fax Machines
- Set-Top Boxes
- Advanced Voice Mail Systems
- Portable Battery Powered Equipment
- Computer Equipment
- Advanced Modems
- Automotive Systems
- Portable Long-Time Monitoring Equipment
- Point-of-Sale Equipment

P (DGS) Pa (TOP VIEV	•	
0	UBAT VBAT RESET SENSE RESET CEOUT	ACTUAL SIZE 3,05 mm x 4,98 mm

During power on, $\overline{\text{RESET}}$ is asserted when the supply voltage (V_{DD} or V_{BAT}) becomes higher than 1.1 V. Thereafter, the supply voltage supervisor monitors V_{DD} and keeps RESET output active as long as V_{DD} remains below the threshold voltage V_{IT}. An internal timer delays the return of the output to the inactive state (high) to ensure proper system reset. The delay time starts after V_{DD} has risen above the threshold voltage V_{IT}.

When the supply voltage drops below the threshold voltage VIT, the output becomes active (low) again.

The TPS3613-01 is available in a 10-pin MSOP package and is characterized for operation over a temperature range of –40°C to 85°C.



typical operating circuit



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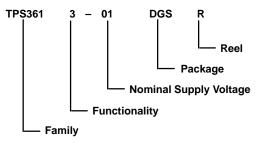
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PACKAGE INFORMATION

Τ _Α	DEVICE NAME	MARKING				
-40°C to 85°C	TPS3613-01DGSR [†]	AFK				

[†] The DGSR passive indicates tape and reel of 2500 parts.

ordering information application specific versions



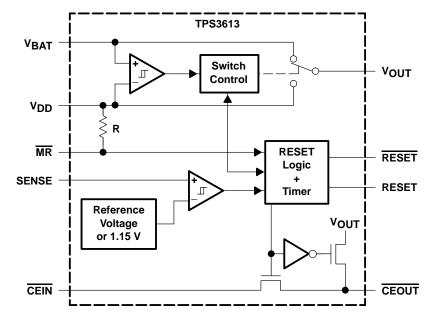
DEVICE NAME	NOMINAL VOLTAGE [‡] , V _{NOM}
TPS3613-01 DGS	Adjustable

[‡] For other threshold voltages, contact the local TI sales office for availability and lead-time.

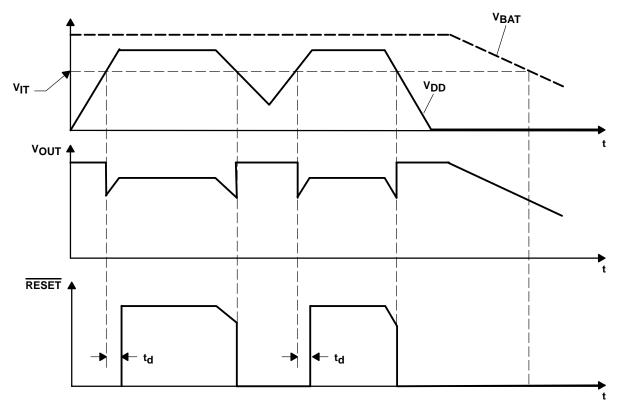
$SENSE > V_{IT}$	V _{DD} > V _{BAT}	MR	CEIN	VOUT	RESET	RESET	CEOUT
0	0	0	0	VBAT	0	1	DIS
0	0	0	1	VBAT	0	1	DIS
0	0	1	0	VBAT	0	1	DIS
0	0	1	1	VBAT	0	1	DIS
0	1	0	0	V _{DD}	0	1	DIS
0	1	0	1	V _{DD}	0	1	DIS
0	1	1	0	V _{DD}	0	1	DIS
0	1	1	1	V _{DD}	0	1	DIS
1	0	0	0	V _{DD}	0	1	DIS
1	0	0	1	V _{DD}	0	1	DIS
1	0	1	0	V _{DD}	1	0	DIS
1	0	1	1	V _{DD}	1	0	EN
1	1	0	0	V _{DD}	0	1	DIS
1	1	0	1	V _{DD}	0	1	DIS
1	1	1	0	V _{DD}	1	0	DIS
1	1	1	1	V _{DD}	1	0	EN



functional schematic



timing diagram





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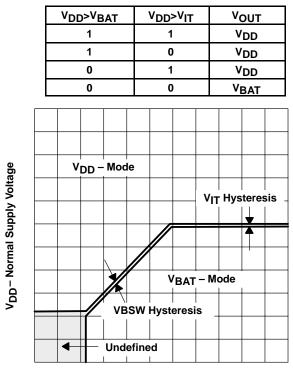
Terminal Functions

TERMI	NAL	I/O	DESCRIPTION
NAME	NO.		
CEIN	5	Ι	Chip-enable input
CEOUT	6	0	Chip-enable output
GND	3	Ι	Ground
MR	4	Ι	Manual reset input
RESET	7	0	Active-high reset output
RESET	9	0	Active-low reset output
SENSE	8	Ι	Adjustable sense input
VBAT	10	Ι	Backup-battery input
V _{DD}	2	I	Input supply voltage
VOUT	1	0	Supply output

detailed description

backup-battery switchover

In case of a brownout or power failure, it may be necessary to preserve the contents of RAM. If a backup battery is installed at V_{BAT}, the device automatically switches the connected RAM to backup power when V_{DD} fails. In order to allow the backup battery (e.g., 3.6-V lithium cells) to have a higher voltage than V_{DD}, these supervisors do not connect V_{BAT} to V_{OUT} when V_{BAT} is greater than V_{DD}. V_{BAT} only connects to V_{OUT} (through a 15- Ω switch) when V_{DD} falls below V_{IT} and V_{BAT} is greater than V_{DD}. When V_{DD} recovers, switchover is deferred either until V_{DD} crosses V_{BAT}, or when V_{DD} rises above the reset threshold V_{IT}. V_{OUT} connects to V_{DD} through a 1- Ω (max) PMOS switch when V_{DD} crosses the reset threshold.



VBAT – Backup-Battery Supply Voltage

Figure 1. V_{DD} – V_{BAT} Switchover



detailed description (continued)

chip-enable signal gating

The internal gating of chip-enable (CE) signals prevents erroneous data from corrupting CMOS RAM during an under-voltage condition. The TPS3613 use a series transmission gate from CEIN to CEOUT. During normal operation (reset not asserted), the CE transmission gate is enabled and passes all CE transitions. When reset is asserted, this path becomes disabled, preventing erroneous data from corrupting the CMOS RAM. The short CE propagation delay from CEIN to CEOUT enables the TPS3613 device to be used with most processors.

The CE transmission gate is disabled and $\overline{\text{CEIN}}$ is high impedance (disable mode) while reset is asserted. During a power-down sequence when V_{DD} crosses the reset threshold, the CE transmission gate is disabled and $\overline{\text{CEIN}}$ immediately becomes high impedance if the voltage at $\overline{\text{CEIN}}$ is high. If $\overline{\text{CEIN}}$ is low when reset is asserted, the CE transmission gate is disabled when $\overline{\text{CEIN}}$ goes high, or 15 μ s after reset asserts, whichever occurs first. This allows the current write cycle to complete during power down. When the CE transmission gate is enabled, the impedance of $\overline{\text{CEIN}}$ appears as a resistor in series with the load at $\overline{\text{CEOUT}}$. The overall device propagation delay through the CE transmission gate depends on V_{OUT}, the source impedance of the drive connected to $\overline{\text{CEIN}}$, and the load at $\overline{\text{CEOUT}}$. To achieve minimum propagation delay, the capacitive load at $\overline{\text{CEOUT}}$ should be minimized, and a low-output-impedance driver is used.

In the disabled mode, the transmission gate is off and an active pullup connects CEOUT to V_{OUT}. This pullup turns off when the transmission gate is enabled.

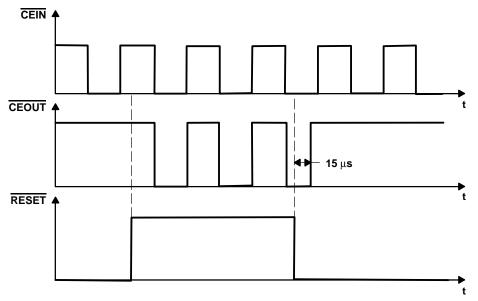


Figure 2. Chip-Enable Timing



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absolute maximum ratings over operating free-air temperature (unless otherwise noted)[†]

Supply voltage: V _{DD} (see Note1)	
MR and SENSE pins (see Note 1)	–0.3 V to (V _{DD} + 0.3 V)
Continuous output current at V _{OUT} : I _O	400 mA
All other pins, I _O	±10 mA
Continuous total power dissipation	. See Dissipation Rating Table
Operating free-air temperature range, T _A	
Storage temperature range, T _A Lead temperature soldering 1,6 mm (1/16 inch) from case for 10 seconds	

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to GND. For reliable operation the device must not be operated at 7 V for more than t=1000h continuously.

DISSIPATION RATING TABLE						
PACKAGE	$T_A \le 25^{\circ}C$ POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 70°C POWER RATING	T _A = 85°C POWER RATING		
DGS	424 mW	3.4 mW/°C	271 mW	220 mW		

recommended operating conditions

	MIN	MAX	UNIT
Supply voltage, V _{DD}	1.65	5.5	V
Battery supply voltage, VBAT	1.5	5.5	V
Input voltage, VI	0	V _{DD} + 0.3	V
High-level input voltage, VIH	0.7 x V _{DD}		V
Low-level input voltage, VIL		0.3 x V _{DD}	V
Continuous output current at VOUT, IO		300	mA
Input transition rise and fall rate at $\overline{\text{MR}}$, $\Delta t/\Delta V$		100	ns/V
Slew rate at V _{DD} or V _{bat}		1	V/µs
Operating free-air temperature range, T _A	-40	85	°C



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electrical characteristics over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
			V _{DD} = 1.8 V I _{OH} = -400 μA	V _{DD} – 0.2 V			
		RESET	$V_{DD} = 3.3 \text{ V}, I_{OH} = -2 \text{ mA}$ $V_{DD} = 5 \text{ V}, I_{OH} = -3 \text{ mA}$	V _{DD} – 0.4 V			
			V_{DD} = 1.8 V, I_{OH} = -20 μ A	V _{DD} – 0.3 V			
∨он	High-level output voltage	RESET	$V_{DD} = 3.3 \text{ V}, I_{OH} = -80 \mu\text{A}$ $V_{DD} = 5 V, I_{OH} = -120 \mu\text{A}$	V _{DD} – 0.4 V			V
-		CEOUT	V _{OUT} = 1.8 V, I _{OH} = -1 mA	V _{OUT} – 0.2 V			
		Enable mode CEIN = V _{OUT}	$V_{OUT} = 3.3 \text{ V}, I_{OH} = -2 \text{ mA}$ $V_{OUT} = 5 \text{ V}, I_{OH} = -5 \text{ mA}$	V _{OUT} – 0.3 V			
		CEOUT Disable mode	V _{OUT} = 3.3 V, I _{OH} = -0.5 mA	V _{OUT} – 0.4 V			
		RESET	$V_{DD} = 1.8 \text{ V}, \text{ I}_{OL} = 400 \mu\text{A}$			0.2	
.,		RESET	$V_{DD} = 3.3 \text{ V}, I_{OL} = 2 \text{ mA}$ $V_{DD} = 5 \text{ V}, I_{OL} = 3 \text{ mA}$			0.4	.,
VOL	Low-level output voltage	CEOUT	V _{OUT} = 1.8 V, I _{OL} = 1.0 mA			0.2	V
		Enable mode CEIN = 0 V	V _{OUT} = 3.3 V, I _{OL} = 2 mA V _{OUT} = 5 V, I _{OL} = 5 mA			0.3	
V _{res}	Power-up reset voltage (se	e Note 2)	$V_{DD} > 1.1 \text{ V or } V_{BAT} > 1.1 \text{ V},$ $I_{OL} = 20 \ \mu\text{A}$			0.4	V
	Normal mode		I _O = 8.5 mA, V _{DD} = 1.8 V, V _{BAT} = 0 V	V _{DD} – 50 mV			
			$I_{O} = 125 \text{ mA},$ $V_{DD} = 3.3 \text{ V}, V_{BAT} = 0 \text{ V}$	V _{DD} – 150 mV			
Vout			I _O = 200 mA, V _{DD} = 5 V, V _{BAT} = 0 V	V _{DD} – 200 mV			V
	Battery-backup mode		I _O = 0.5 mA, V _{BAT} = 1.5 V, V _{DD} = 0 V	V _{BAT} – 20 mV			
			I _O = 7.5 mA, V _{BAT} = 3.3 V, V _{DD} = 0 V	V _{BAT} – 113 mV			
Baad	V _{DD} to V _{OUT} on-resistance	e	$V_{DD} = 5 V$		0.6	1	Ω
RDS(on)	VBAT to VOUT on-resistan	се	V _{BAT} = 3.3 V		8	15	52
VIT	Negative-going input threst (see Note 3)	nold voltage		1.13	1.15	1.17	V
v.	Hystorosia	Sense	1.1 V < V _{IT} < 1.65 V		12		m\/
V _{hys}	Hysteresis	V _{BSW} (see Note 4)	V _{DD} = 1.8 V		55		mV
Ιн	High-level input current		MR = 0.7 x V _{DD} , V _{DD} = 5 V	-33		-76	μA
lı∟	Low-level input current		$\overline{\text{MR}} = 0 \text{ V}, \qquad \qquad \text{V}_{\text{DD}} = 5 \text{ V}$	-110		-255	
lı	Input current	SENSE	V _{DD} = 1.15 V	-25		25	nA
DD	V _{DD} supply current		V _{OUT} = V _{DD} V _{OUT} = V _{BAT}			40 40	μA
IBAT	VBAT supply current		V _{OUT} = V _{DD} V _{OUT} = V _{BAT}	-0.1		0.1 0.5	μA
	CEIN leakage current		Disable mode, $V_I < V_{DD}$			±1	μA
l _{lkg}							

NOTES: 2. The lowest supply voltage at which $\overrightarrow{\text{RESET}}$ becomes active. $t_{r,(VDD)} \ge 15 \,\mu\text{s/V}$. 3. To ensure best stability of the threshold voltage, a bypass capacitor (ceramic, 0.1 μ F) should be placed near to the supply terminals. 4. For V_{DD} < 1.6 V, V_{OUT} switches to V_{BAT} regardless of V_{BAT}



TPS3613-01 ADJUSTABLE BATTERY-BACKUP SUPERVISOR FOR RAM RETENTION SLVS340B – DECEMBER 2000 – REVISED DECEMBER 2002

timing requirements at RL = 1 M\Omega, CL = 50 pF, TA = –40°C to 85°C

PARAMETER TEST CONDITIONS			MIN	TYP	MAX	UNIT		
tw	Pulse width	SENSE	$V_{IH} = V_{IT} + 0.2 V,$	$V_{IL} = V_{IT} - 0.2 V$	6			μs

switching characteristics at R_L = 1 MΩ, C_L= 50 pF, T_A = -40°C to 85°C

	PARAM	ETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
td	Delay time		$\frac{V_{SENSE} \ge V_{IT} + 0.2 \text{ V},}{MR \ge 0.7 \text{ x } V_{DD},}$ See timing diagram	60	100	140	ms	
^t PLH	Propagation (delay) time, low-to-high-level output	50% RESET to 50% CEOUT	V _{OUT} = V _{IT}		15		μs	
		50% $\overline{\text{CEIN}}$ to 50% $\overline{\text{CEOUT}}$, C _L = 50 pF only (see Note 5)	V _{DD} = 1.8 V		5	15	ns	
			V _{DD} = 3.3 V		1.6	5		
			$V_{DD} = 5 V$		1	3		
^t PHL	Propagation (delay) time, high-to-low-level output		SENSE to RESET	$V_{IL} = V_{IT} - 0.2 \text{ V},$ $V_{IH} = V_{IT} + 0.2 \text{ V}$		2	5	μs
		MR to RESET	$\label{eq:VSENSE} \begin{array}{l} V_{SENSE} \geq V_{IT} + 0.2 \; V, \\ V_{IL} = 0.3 \; x \; V_{DD}, \\ V_{IH} = 0.7 \; x \; V_{DD} \end{array}$		0.1	1	μs	
	Transition time	V _{DD} to V _{BAT}	$V_{IH} = V_{BAT} + 0.2 V,$ $V_{IL} = V_{BAT} - 0.2 V,$ $V_{BAT} < V_{IT}$			3	μs	

NOTE 5: Assured by design

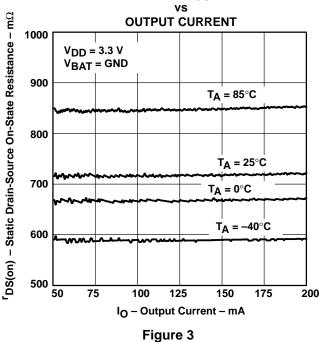


TYPICAL CHARACTERISTICS

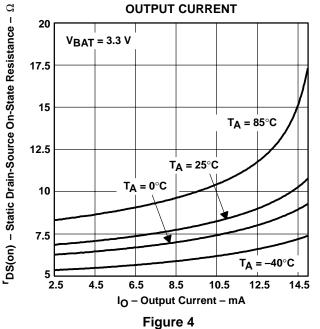
Table of Graphs

			FIGURE
	Static drain-source on-state resistance (V _{DD} to V _{OUT})	vs Output current	3
^r DS(on)	Static drain-source on-state resistance (VBAT to VOUT)	vs Output current	4
、 <i>,</i>	Static drain-source on-state resistance (CEIN to CEOUT)	vs Input voltage at CEIN	5
IDD	Supply current	vs Supply voltage	6
VIT	Input threshold voltage at RESET	vs Free-air temperature	7
	High-level output voltage at RESET		8, 9
Vон	High-level output voltage at CEOUT	vs High-level output current	10, 11, 12, 13
	Low-level output voltage at RESET	vs Low-level output current	14, 15
VOL	Low-level output voltage at CEOUT	vs Low-level output current	16, 17

STATIC DRAIN-SOURCE ON-STATE RESISTANCE (V_{DD} to V_{OUT})

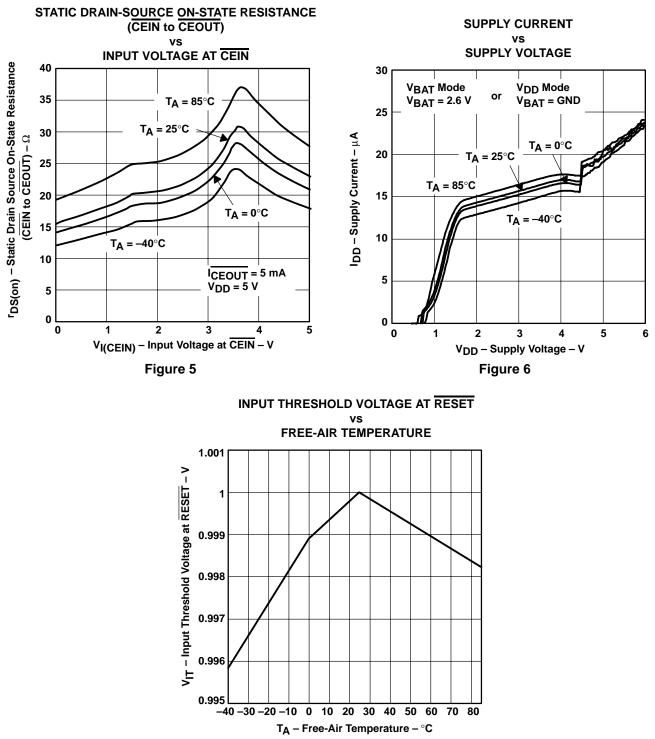


STATIC DRAIN-SOURCE ON-STATE RESISTANCE (V_{BAT} to V_{OUT}) vs



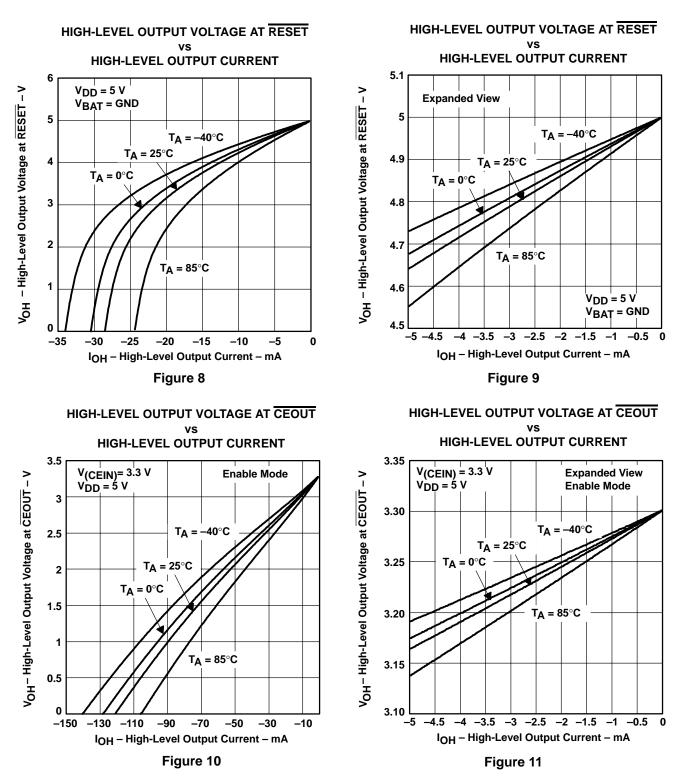






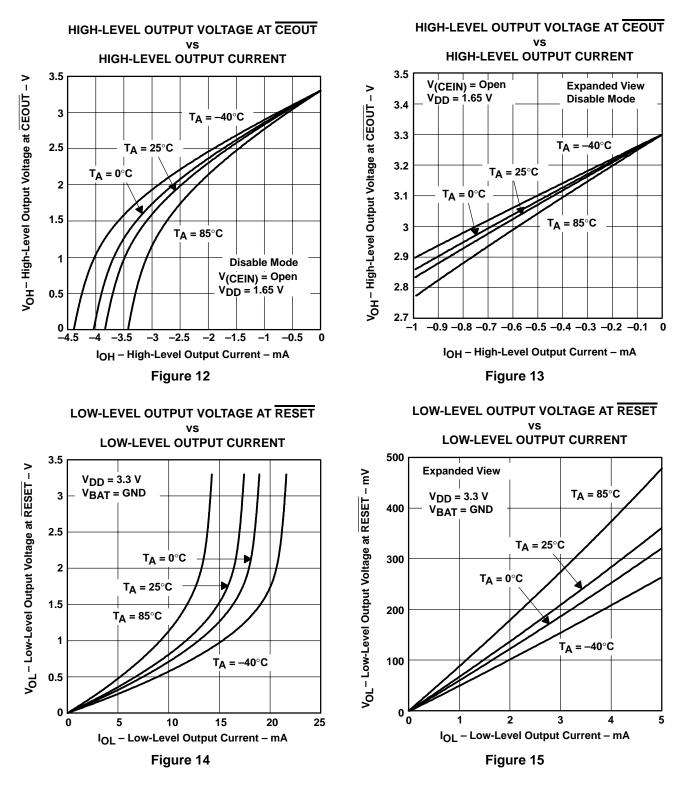


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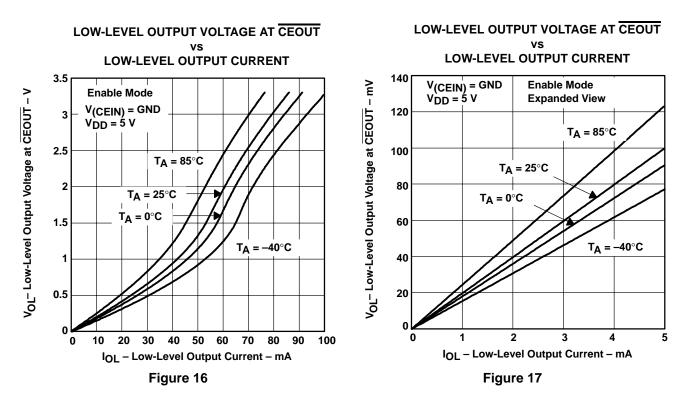








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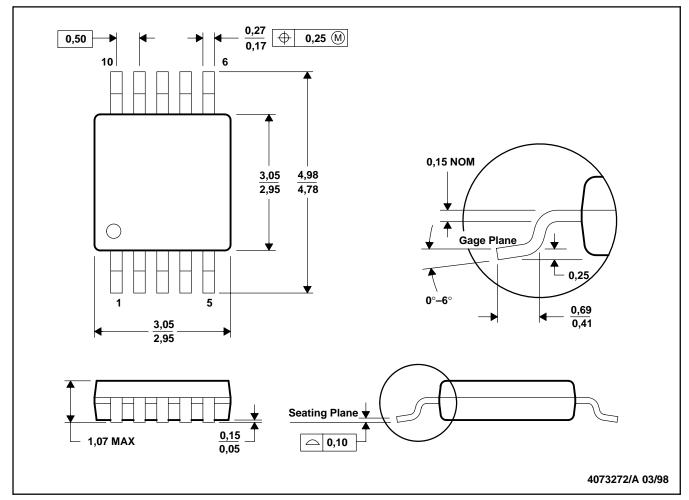


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MECHANICAL DATA

DGS (S-PDSO-G10)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion.



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